resonating probes. Thus Examiner's citation of prior art regarding horizontal dielectric probes is inaccurate.

Regarding the Examiner's repeated citation of Cusak's publication as anticipating the present invention, we respectfully disagree: Cusak discloses an entirely dielectric cylindrical probe, without metal mantle between the central conductor and the ground walls; in addition Cusak's probe slides inside a cylindrical coaxial airline structure, whereas we claim a metal-dielectric combination probe sliding inside a slabline; at this point it seems very important to recapitulate and clarify the facts and the various techniques used and referred to in this application, by showing a cross section of all hereby discussed tuner probes (Figures i to iv):

- 1. Cusak discloses a horizontal wideband probe made entirely of dielectric material inserted into a slotted coaxial airline (Figure i).
- 2. The present invention discloses a horizontal wideband combination metallicdielectric probe, inserted into a slabline (Figure ii).
- 3. Tsironis (US patent 6,297,649) discloses a vertical narrowband (resonant) contacting metallic probe (Figure iii).
- 4. Prior art (US patent 6,674,293 et al.) uses exclusively vertical wideband metallic probes inserted into a slabline (Figure iv).

By comparing carefully Figures i and ii to Figures i to iv below it should be obvious to a person with ordinary skill in the art, that the hereby claimed apparatus uses different kind of probes as in any previous publication. This invention does not claim proprietorship of a tuner in general, nor a translation mechanism, or a test port and an idle port, a tuner housing etc. This invention claims proprietorship of an original RF Application No. 10/702,506

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probe structure in such tuners, which said probe structure has neither been used, nor

described before.

In addition, even though we understand that the functioning of an apparatus is not

sufficient ground for allowing a patent, but considering this to be important

background information for the Examiner, in order to allow a better distinction of the

various cases, we provide, in Figure v, typical reflection factor behavior of the probes

described here.

We therefore respectfully request the Examiner to revise his decision and allow the

claims of the present application.

Respectfully submitted

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